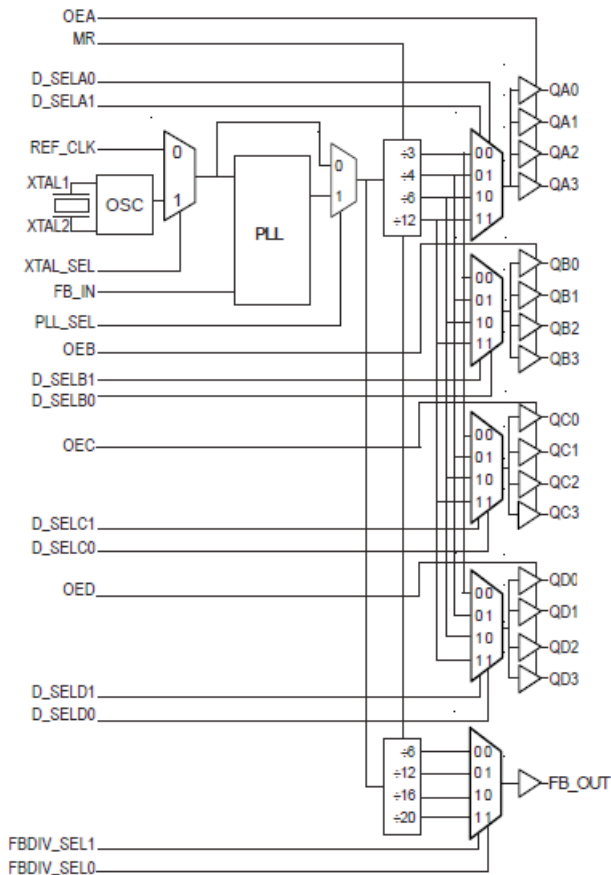


GENERAL DESCRIPTION

The 8761I is a low voltage, low skew PCI / PCI-X clock generator. The 8761I has a selectable REF_CLK or crystal input. The REF_CLK input accepts LVCMOS or LVTTTL input levels. The 8761I has a fully integrated PLL along with frequency configurable clock and feedback outputs for multiplying and regenerating clocks with “zero delay”. Using a 20MHz or 25MHz crystal or a 33.333MHz or 66.666MHz reference frequency, the 8761I will generate output frequencies of 33.333MHz, 66.666MHz, 100MHz and 133.333MHz simultaneously.

The low impedance LVCMOS/LVTTTL outputs of the 8761I are designed to drive 50Ω series or parallel terminated transmission lines.

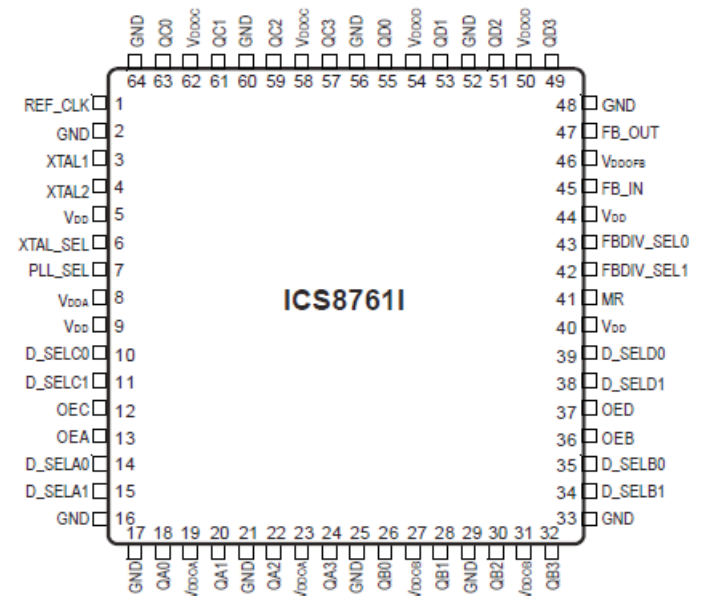
BLOCK DIAGRAM



FEATURES

- Fully integrated PLL
- Seventeen LVCMOS/LVTTTL outputs, 15Ω typical output impedance
- Selectable crystal oscillator interface or LVCMOS/LVTTTL REF_CLK
- Maximum output frequency: 166.67MHz
- Maximum crystal input frequency: 40MHz
- Maximum REF_CLK input frequency: 83.33MHz
- Individual banks with selectable output dividers for generating 33.333MHz, 66.66MHz, 100MHz and 133.333MHz simultaneously
- Separate feedback control for generating PCI / PCI-X frequencies from a 20MHz or 25MHz crystal or 33.333MHz or 66.666MHz reference frequency
- Cycle-to-cycle jitter: 70ps (maximum)
- Period jitter, RMS: 17ps (maximum)
- Output skew: 250ps (maximum)
- Bank skew: 50ps (maximum)
- Static phase offset: 0 ± 150 ps (maximum)
- Full 3.3V or 3.0V core, 2.5V multiple output supply modes
- -40°C to 85°C ambient operating temperature
- Available in both standard and lead-free RoHS-compliant packages

PIN ASSIGNMENT



64-Lead LQFP
10mm x 10mm x 1.4mm package body
Y package
Top View

TABLE 1. PIN DESCRIPTIONS

Number	Name	Type		Description
1	REF_CLK	Input	Pulldown	Reference clock input. LVCMOS / LVTTTL interface levels.
2, 16, 17, 21, 25, 29, 33, 48, 52, 56, 60, 64	GND	Power		Power supply ground.
3, 4	XTAL1, XTAL2	Input		Crystal oscillator interface. XTAL1 is the input. XTAL2 is the output.
5, 9, 40, 44	V _{DD}	Power		Core supply pins.
6	XTAL_SEL	Input	Pullup	Selects between crystal oscillator or reference clock as the PLL reference source. Selects XTAL inputs when HIGH. Selects REF_CLK when LOW. LVCMOS / LVTTTL interface levels.
7	PLL_SEL	Input	Pullup	Selects between PLL and bypass mode. When HIGH, selects PLL. When LOW, selects reference clock. LVCMOS / LVTTTL interface levels.
8	V _{DDA}	Power		Analog supply pin. See Applications Note for filtering.
10, 11	D_SELCO, D_SELCO1	Input	Pulldown	Selects divide value for Bank C outputs as described in Table 3. LVCMOS / LVTTTL interface levels.
12	OEC	Input	Pullup	Determines state of Bank C outputs. When HIGH, outputs are enabled. When LOW, outputs are disabled. LVCMOS / LVTTTL interface levels.
13	OEA	Input	Pullup	Determines state of Bank A outputs. When HIGH, outputs are enabled. When LOW, outputs are disabled. LVCMOS / LVTTTL interface levels.
14, 15	D_SELA0, D_SELA1	Input	Pulldown	Selects divider value for Bank A outputs as described in Table 3. LVCMOS / LVTTTL interface levels.
18, 20, 22, 24	QA0, QA1, QA2, QA3	Output		Bank A clock outputs. 15Ω typical output impedance. LVCMOS / LVTTTL interface levels.
19, 23	V _{DDOA}	Power		Output supply pins for Bank A outputs.
26, 28, 30, 32	QB0, QB1, QB2, QB3	Output		Bank B clock outputs. 15Ω typical output impedance. LVCMOS / LVTTTL interface levels.
27, 31	V _{DDOB}	Power		Output supply pins for Bank B outputs.
34, 35	D_SELB1, D_SELBO	Input	Pulldown	Selects divider value for Bank B outputs as described in Table 3. LVCMOS / LVTTTL interface levels.
36	OEB	Input	Pullup	Determines state of Bank B outputs. When HIGH, outputs are enabled. When LOW, outputs are disabled. LVCMOS / LVTTTL interface levels.
37	OED	Input	Pullup	Determines state of Bank D outputs. When HIGH, outputs are enabled. When LOW, outputs are disabled. LVCMOS / LVTTTL interface levels.
38, 39	D SELD1, D SELDO	Input	Pulldown	Selects divider value for Bank D outputs as described in Table 3. LVCMOS / LVTTTL interface levels.
41	MR	Input	Pulldown	Active HIGH Master reset. When logic HIGH, the internal dividers are reset causing the outputs to go low. When logic LOW, the internal dividers and the outputs are enabled. LVCMOS / LVTTTL interface levels.
42	FBDIV_SEL1	Input	Pulldown	Selects divider value for bank feedback output as described in Table 3. LVCMOS / LVTTTL interface levels.
43	FBDIV_SELO	Input	Pullup	Selects divider value for bank feedback output as described in Table 3. LVCMOS / LVTTTL interface levels.
45	FB_IN	Input	Pulldown	Feedback input to phase detector for generating clocks with “zero delay”. LVCMOS / LVTTTL interface levels.

Number	Name	Type	Description
46	V _{DDO_{FB}}	Power	Output supply pin for FB_Out output.
47	FB_OUT	Output	Feedback output. Connect to FB_IN. 15Ω typical output impedance. LVCMOS / LVTTTL interface levels.
49, 51, 53, 55	QD3, QD2, QD1, QD0	Output	Bank D clock outputs. 15Ω typical output impedance. LVCMOS / LVTTTL interface levels.
50, 54	V _{DDO_D}	Power	Output supply pins for Bank D outputs.
57, 59, 61, 63	QC3, QC2, QC1, QC0	Output	Bank C clock outputs. 15Ω typical output impedance. LVCMOS / LVTTTL interface levels.
58, 62	V _{DDO_C}	Power	Output supply pins for Bank C outputs.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

TABLE 2. PIN CHARACTERISTICS

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
R _{PULLUP}	Input Pullup Resistor				51	kΩ
R _{PULLDOWN}	Input Pulldown Resistor				51	kΩ
C _{PD}	Power Dissipation Capacitance (per output); NOTE 1	V _{DD} , V _{DDA} = 3.465V; V _{DDOx} = 3.465V			9	pF
		V _{DD} , V _{DDA} = 3.465V; V _{DDOx} = 2.625V			11	pF
R _{OUT}	Output Impedance			15		Ω

NOTE 1: V_{DDOx} denotes V_{DDO_A}, V_{DDO_B}, V_{DDO_C}, V_{DDO_D}, V_{DDO_{FB}}.

TABLE 3A. OUTPUT CONTROL PIN FUNCTION TABLE

Inputs					Outputs			
MR	OEA	OEB	OEC	OED	QA0:QA3	QB0:QB3	QC0:QC3	QD0:QD3
1	1	1	1	1	LOW	LOW	LOW	LOW
0	1	1	1	1	Active	Active	Active	Active
X	0	0	0	0	HiZ	HiZ	HiZ	HiZ

TABLE 3B. OPERATING MODE FUNCTION TABLE

Inputs	Operating Mode
PLL_SEL	
0	Bypass
1	PLL

TABLE 3C. PLL INPUT FUNCTION TABLE

Inputs	
XTAL_SEL	PLL Input
0	REF_CLK
1	XTAL Oscillator

TABLE 3D. CONTROL FUNCTION TABLE

Inputs					Outputs		
					PLL_SEL =1	Frequency	
D_SELx1	D_SELx0	FBDIV_SEL1	FBDIV_SEL0	Reference Frequency Range (MHz)	QX0:QX3	QX0:QX3 (MHz)	FB_OUT (MHz)
0	0	0	0	41.6 - 83.33	x 2	83.33 - 166.67	41.6 - 83.33
0	0	0	1	20.83 - 41.67	x 4	83.33 - 166.67	20.83 - 41.67
0	0	1	0	15.62 - 31.25	x 5.33	83.33 - 166.67	15.62 - 31.25
0	0	1	1	12.5 - 25	x 6.67	83.33 - 166.67	12.5 - 25
0	1	0	0	41.6 - 83.33	x 1.5	62.4 - 125	41.6 - 83.33
0	1	0	1	20.83 - 41.67	x 3	62.4 - 125	20.83 - 41.67
0	1	1	0	15.62 - 31.25	x 4	62.4 - 125	15.62 - 31.25
0	1	1	1	12.5 - 25	x 5	62.4 - 125	12.5 - 25
1	0	0	0	41.6 - 83.33	x 1	41.6 - 83.33	41.6 - 83.33
1	0	0	1	20.83 - 41.67	x 2	41.6 - 83.33	20.83 - 41.67
1	0	1	0	15.62 - 31.25	x 2.67	41.6 - 83.33	15.62 - 31.25
1	0	1	1	12.5 - 25	x 3.33	41.6 - 83.33	12.5 - 25
1	1	0	0	41.6 - 83.33	÷ 2	20.8 - 41.67	41.6 - 83.33
1	1	0	1	20.83 - 41.67	÷ 1	20.8 - 41.67	20.83 - 41.67
1	1	1	0	15.62 - 31.25	x 1.33	20.8 - 41.67	15.62 - 31.25
1	1	1	1	12.5 - 25	x 1.67	20.8 - 41.67	12.5 - 25

NOTE: D_SELX1 denotes D_SELA1, D_SELB1, D_SEL C1, and D_SELD1. D_SELX0 denotes D_SELA0, D_SELB0, D_SEL C0, and D_SELD0. QX0:QX3 denotes QA0:QA3, QB0:QB3, QC0:QC3, and QD0:QD3.

TABLE 3E. CONTROL FUNCTION TABLE (PCI CONFIGURATION)

Inputs					Outputs		
					PLL_SEL = 1	Frequency	
D_SELx1	D_SELx0	FBDIV_SEL1	FBDIV_SEL0	Reference Frequency (MHz)	QX0:QX3	QX0:QX3 (MHz)	FB_OUT (MHz)
0	0	0	0	66.67	x 2	133	66.67
0	0	0	1	33.33	x 4	133	33.33
0	0	1	0	25	x 5.33	133	25
0	0	1	1	20	x 6.67	133	20
0	1	0	0	66.67	x 1.5	100	66.67
0	1	0	1	33.33	x 3	100	33.33
0	1	1	0	25	x 4	100	25
0	1	1	1	20	x 5	100	20
1	0	0	0	66.67	x 1	66.67	66.67
1	0	0	1	33.33	x 2	66.67	33.33
1	0	1	0	25	x 2.67	66.67	25
1	0	1	1	20	x 3.33	66.67	20
1	1	0	0	66.67	÷ 2	33.33	66.67
1	1	0	1	33.33	÷ 1	33.33	33.33
1	1	1	0	25	x 1.33	33.33	25
1	1	1	1	20	x 1.67	33.33	20

NOTE: D_SELx1 denotes D_SELA1, D_SELB1, D_SEL C1, and D_SELD1. D_SELx0 denotes D_SELA0, D_SELB0, D_SEL C0, and D_SELD0. QX0:QX3 denotes QA0:QA3, QB0:QB3, QC0:QC3, and QD0:QD3.

ABSOLUTE MAXIMUM RATINGS

Supply Voltage, V_{DD}	4.6V
Inputs, V_I	-0.5V to $V_{DD} + 0.5V$
Outputs, V_O	-0.5V to $V_{DDOX} + 0.5V$
Package Thermal Impedance, θ_{JA}	41.1°C/W (0 lfpm)
Storage Temperature, T_{STG}	-65°C to 150°C

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

TABLE 4A. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = V_{DDA} = V_{DDOX} = 3.3V \pm 5\%$ OR $2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Core Supply Voltage		3.135	3.3	3.465	V
V_{DDA}	Analog Supply Voltage		3.135	3.3	3.465	V
V_{DDOX}	Output Supply Voltage; NOTE 1		3.135	3.3	3.465	V
			2.375	2.5	2.625	V
I_{DD}	Power Supply Current				175	mA
I_{DDA}	Analog Supply Current				55	mA
I_{DDOX}	Output Supply Current; NOTE 2				25	mA

NOTE 1: V_{DDOX} denotes V_{DDOA} , V_{DDOB} , V_{DDOC} , V_{DDOD} , and V_{DDOFB} .

NOTE 2: I_{DDOX} denotes I_{DDOA} , I_{DDOB} , I_{DDOC} , I_{DDOD} , and I_{DDOFB} .

TABLE 4B. LVCMOS/LVTTL DC CHARACTERISTICS, $V_{DD} = V_{DDA} = 3.3V \pm 5\%$, $V_{DDOX} = 3.3V \pm 5\%$ OR $2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage	OEA:OED, XTAL_SEL, MR, D_SELAx, D_SELBx, FB_IN, D_SELcx, D_SELDx, PLL_SEL, FBDIV_SEL0, FBDIV_SEL1	2		$V_{DD} + 0.3$	V
		REF_CLK	2		$V_{DD} + 0.3$	V
V_{IL}	Input Low Voltage	OEA:OED, XTAL_SEL, MR, D_SELAx, D_SELBx, FB_IN, D_SELcx, D_SELDx, PLL_SEL, FBDIV_SEL0, FBDIV_SEL1	-0.3		0.8	V
		REF_CLK	-0.3		1.3	V
I_{IH}	Input High Current	D_SELAx, D_SELBx, FB_IN, MR, D_SELcx, D_SELDx, REF_CLK, FBDIV_SEL1	$V_{DD} = V_{IN} = 3.465\text{V}$ or 2.625V		150	μA
		XTAL_SEL, PLL_SEL, FBDIV_SEL0, OEA:OED	$V_{DD} = V_{IN} = 3.465\text{V}$ or 2.625V		5	μA
I_{IL}	Input Low Current	D_SELAx, D_SELBx, FB_IN, MR, D_SELcx, D_SELDx, REF_CLK, FBDIV_SEL1	$V_{DD} = 3.465\text{V}$ or 2.625V , $V_{IN} = 0\text{V}$	-5		μA
		XTAL_SEL, PLL_SEL, FBDIV_SEL0, OEA:OED	$V_{DD} = 3.465\text{V}$ or 2.625V , $V_{IN} = 0\text{V}$	-150		μA
V_{OH}	Output High Voltage; NOTE 1	$V_{DDOX} = 3.465\text{V}$	2.6			V
		$V_{DDOX} = 2.625\text{V}$	1.8			
V_{OL}	Output Low Voltage; NOTE 1	$V_{DDOX} = 3.465\text{V}$ or 2.625V			0.5	V
I_{OZL}	Output Tristate Current Low		-5			μA
I_{OZH}	Output Tristate Current High				5	μA

NOTE 1: Outputs terminated with 50Ω to $V_{DDOX}/2$. See Parameter Measurement Information section, "Output Load Test Circuit".

TABLE 5. CRYSTAL CHARACTERISTICS

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation		Fundamental			
Frequency		10		38	MHz
Equivalent Series Resistance (ESR)				70	Ω
Shunt Capacitance			7		pF
Drive Level				1	mW

TABLE 6. PLL INPUT REFERENCE CHARACTERISTICS, $V_{DD} = V_{DDA} = V_{DDOX} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{REF}	Reference Frequency		12.5		83.33	MHz

TABLE 7A. AC CHARACTERISTICS, $V_{DD} = V_{DDA} = V_{DDOX} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{MAX}	Output Frequency				166.67	MHz
$t(\emptyset)$	Static Phase Offset; NOTE 1, 7	$f = 50\text{MHz}$	-150		150	ps
$tsk(b)$	Bank Skew; NOTE 2, 6				50	ps
$tsk(o)$	Output Skew; NOTE 3, 6				250	ps
$t_{jit(cc)}$	Cycle-to-Cycle Jitter; 6	$f = 50\text{MHz}$; NOTE 4, 7			70	ps
		$f = 25\text{MHz XTAL}$, 133.3MHz out			190	ps
$t_{jit(per)}$	Period Jitter, RMS; NOTE 4, 6, 7, 8				17	ps
t_L	PLL Lock Time				1	ms
t_R / t_F	Output Rise/Fall Time	20% to 80%	250		800	ps
odc	Output Duty Cycle; NOTE 5, 7		45		55	%

NOTE 1: Defined as the time difference between the input reference clock and the average feedback input signal when the PLL is locked and the input reference frequency is stable. Measured from $V_{DD}/2$ of the input to $V_{DDOX}/2$ of the output.

NOTE 2: Defined as skew within a bank of outputs at the same voltages and with equal load conditions.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at $V_{DDOX}/2$.

NOTE 4: Jitter performance using LVCMOS inputs.

NOTE 5: Measured using REF_CLK. For XTAL input, refer to Application Note.

NOTE 6: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 7: Tested with $D_SELXX = 10$ (divide by 6); $FBDIV_SEL = 00$ (divide by 6).

NOTE 8: This parameter is defined as an RMS value.

TABLE 7B. AC CHARACTERISTICS, $V_{DD} = V_{DDA} = 3.3V \pm 5\%$, $V_{DDOX} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{MAX}	Output Frequency				166.67	MHz
$t(\emptyset)$	Static Phase Offset; NOTE 1, 7	$f = 50\text{MHz}$	-350		20	ps
$tsk(b)$	Bank Skew; NOTE 2, 6				50	ps
$tsk(o)$	Output Skew; NOTE 3, 6				250	ps
$t_{jit(cc)}$	Cycle-to-Cycle Jitter; NOTE 6	$f = 50\text{MHz}$; NOTE 4, 7			70	ps
		$f = 25\text{MHz XTAL}$, 133.3MHz out			190	ps
$t_{jit(per)}$	Period Jitter, RMS; NOTE 4, 6, 7, 8				17	ps
t_L	PLL Lock Time				1	ms
t_R / t_F	Output Rise/Fall Time	20% to 80%	250		800	ps
odc	Output Duty Cycle; NOTE 5, 7		45		55	%

NOTE 1: Defined as the time difference between the input reference clock and the average feedback input signal when the PLL is locked and the input reference frequency is stable. Measured from $V_{DD}/2$ of the input to $V_{DDOX}/2$ of the output.

NOTE 2: Defined as skew within a bank of outputs at the same voltages and with equal load conditions.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at $V_{DDOX}/2$.

NOTE 4: Jitter performance using LVCMOS inputs.

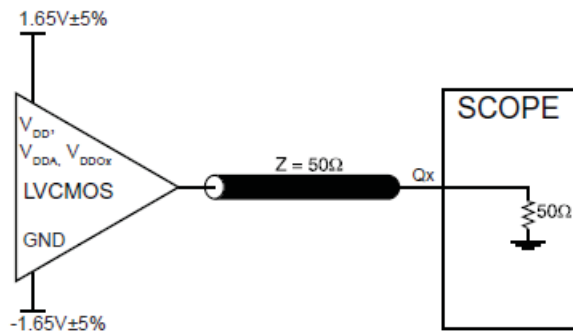
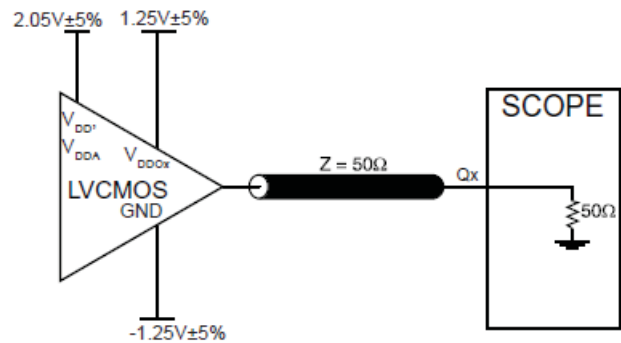
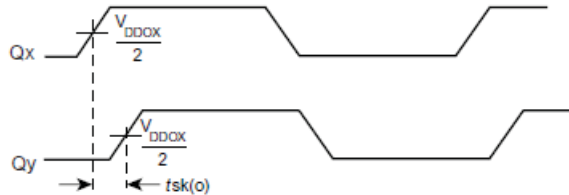
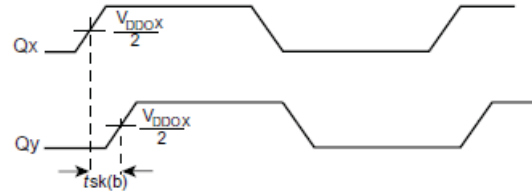
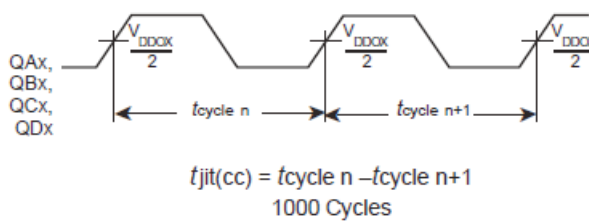
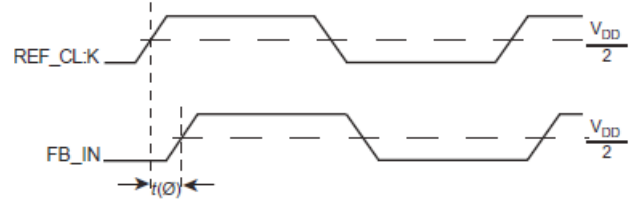
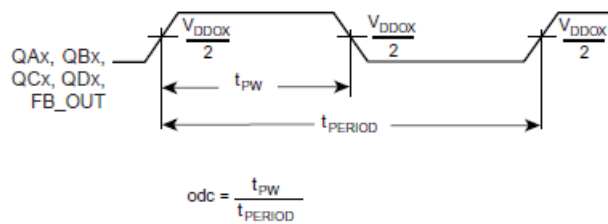
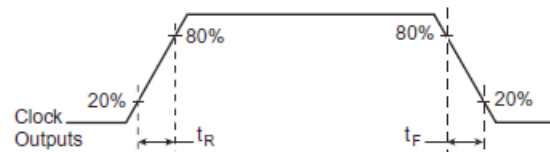
NOTE 5: Measured using REF_CLK. For XTAL input, refer to Application Note.

NOTE 6: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 7: Tested with $D_SELXX = 10$ (divide by 6); $FBDIV_SEL = 00$ (divide by 6).

NOTE 8: This parameter is defined as an RMS value

PARAMETER MEASUREMENT INFORMATION


3.3V CORE/3.3V OUTPUT LOAD AC TEST CIRCUIT

3.3V CORE/2.5V OUTPUT LOAD AC TEST CIRCUIT

OUTPUT SKEW

BANK SKEW (Where X denotes outputs in the same Bank)

CYCLE-TO-CYCLE JITTER

STATIC PHASE OFFSET

OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD

OUTPUT RISE/FALL TIME

APPLICATION INFORMATION

POWER SUPPLY FILTERING TECHNIQUES

As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. The 8761I provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL. V_{DD} , V_{DDA} , and V_{DDOX} should be individually connected to the power supply plane through vias, and bypass capacitors should be used for each pin. To achieve optimum jitter performance, power supply isolation is required. *Figure 1* illustrates how a ferrite bead along with a $10\mu\text{F}$ and a $.01\mu\text{F}$ bypass capacitor should be connected to each V_{DDA} .

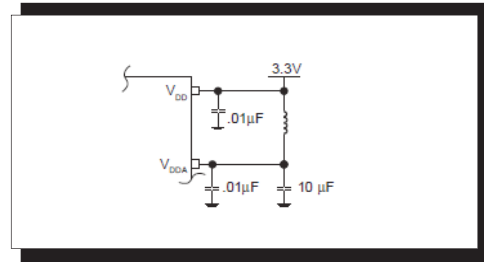


FIGURE 1. POWER SUPPLY FILTERING

CRYSTAL INPUT INTERFACE

The 8761I crystal interface is shown in *Figure 2*. While layout the PC Board, it is recommended to provide C1 and C2 spare footprints for frequency fine tuning. For an 18pF parallel resonant

crystal, the C1 and C2 are expected to be $\sim 10\text{pF}$ and $\sim 5\text{pF}$ respectively.

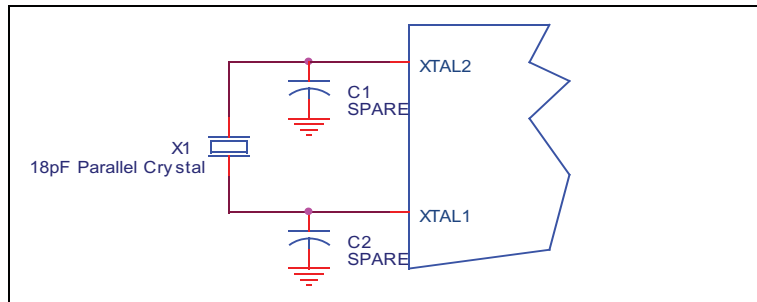


FIGURE 2. CRYSTAL INPUT INTERFACE

RECOMMENDATIONS FOR UNUSED INPUT AND OUTPUT PINS

INPUTS:

CRYSTAL INPUT:

For applications not requiring the use of the crystal oscillator input, both XTAL_IN and XTAL_OUT can be left floating. Though not required, but for additional protection, a 1k Ω resistor can be tied from XTAL_IN to ground.

REF_CLK INPUT:

For applications not requiring the use of the reference clock, it can be left floating. Though not required, but for additional protection, a 1k Ω resistor can be tied from the REF_CLK to ground.

LVC MOS CONTROL PINS:

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A 1k Ω resistor can be used.

OUTPUTS:

LVC MOS OUTPUT:

All unused LVC MOS output can be left floating. We recommend that there is no trace attached.

SCHEMATIC EXAMPLE

Figure 3 shows a schematic example of the 87611. In this example, the input is driven by an 18pF parallel crystal. The decoupling capacitors should be physically located near the power

pin. For 87611, the unused clock outputs can be left floating. The optional C1 and C2 are spare footprints for frequency fine tuning.

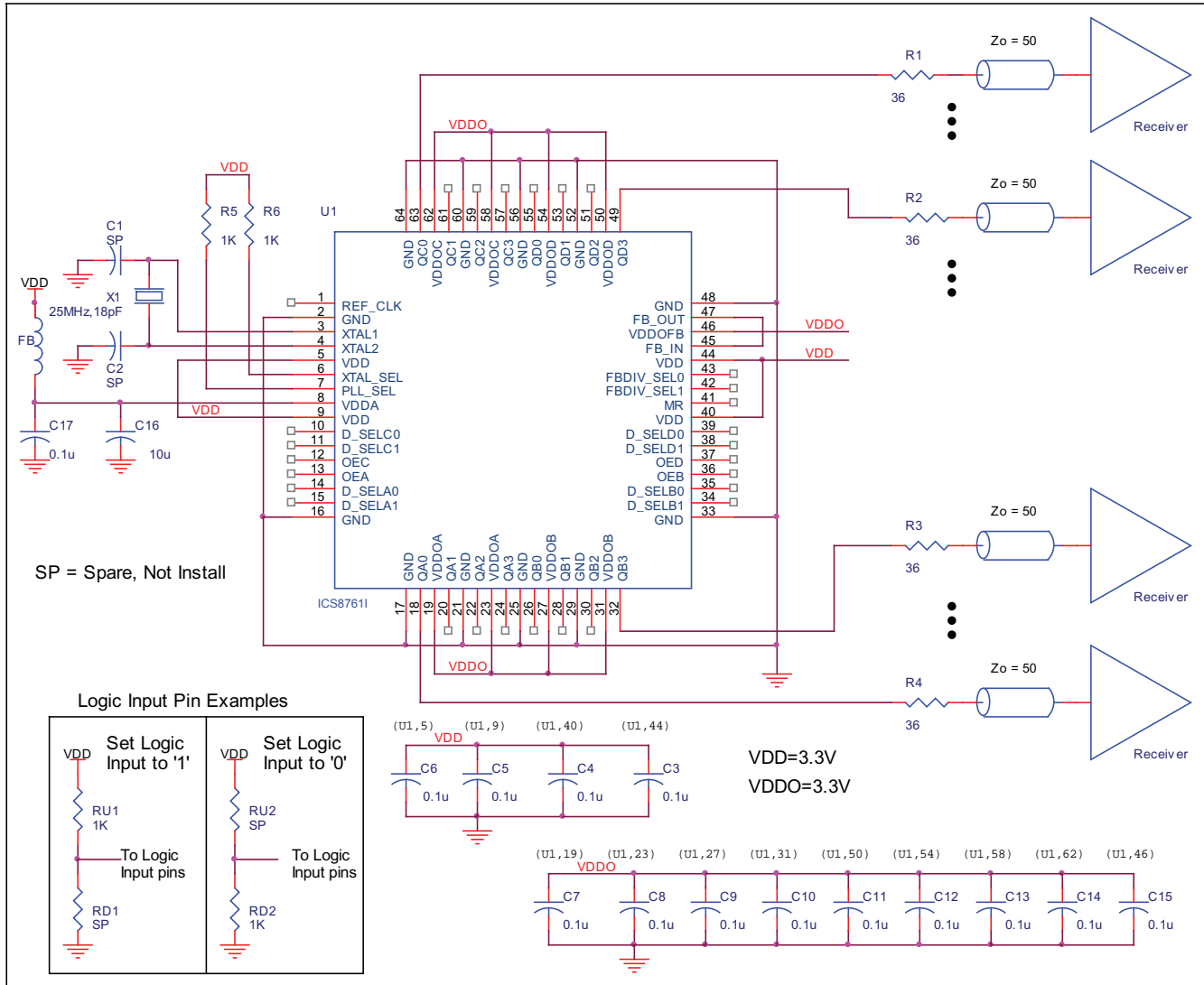


FIGURE 3. 87611 CLOCK GENERATOR SCHEMATIC EXAMPLE

RELIABILITY INFORMATION

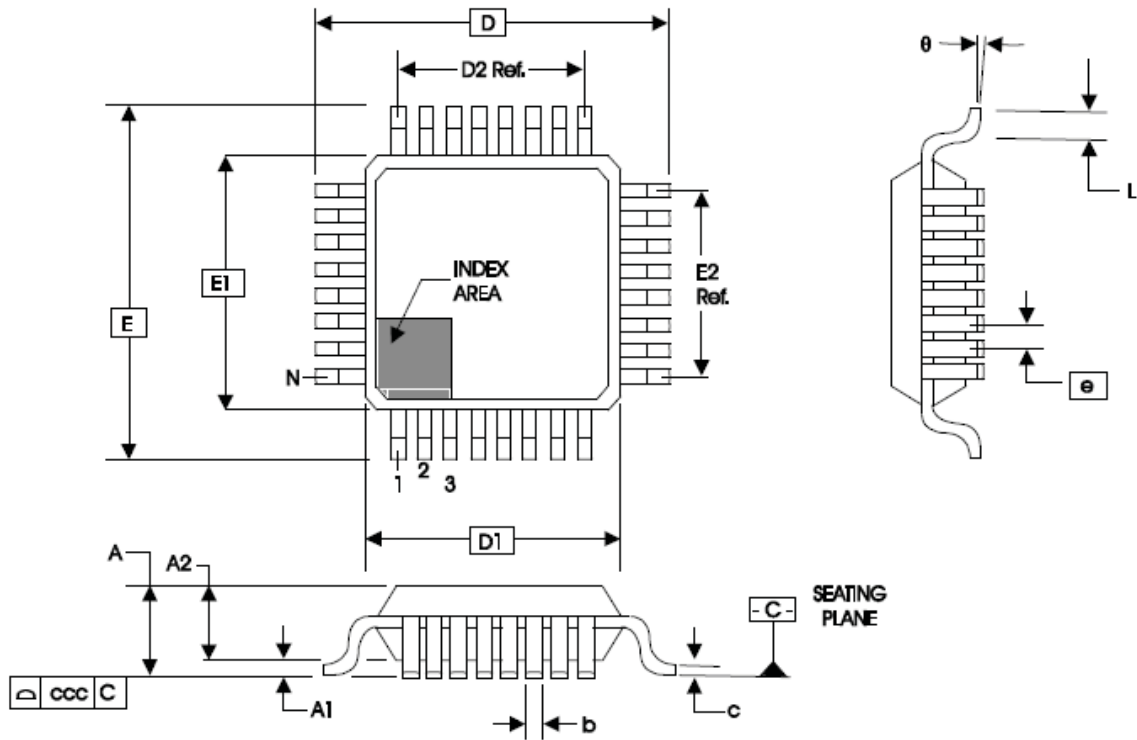
TABLE 8. θ_{JA} vs. AIR FLOW TABLE FOR 64 LEAD LQFP

θ_{JA} by Velocity (Linear Feet per Minute)			
	0	200	500
Single-Layer PCB, JEDEC Standard Test Boards	58.8°C/W	48.5°C/W	43.2°C/W
Multi-Layer PCB, JEDEC Standard Test Boards	41.1°C/W	35.8°C/W	33.6°C/W

NOTE: Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.

TRANSISTOR COUNT

The transistor count for 8761I is: 6040

PACKAGE OUTLINE - Y SUFFIX FOR 64 LEAD LQFP

TABLE 9. PACKAGE DIMENSIONS

JEDEC VARIATION ALL DIMENSIONS IN MILLIMETERS			
SYMBOL	BCD		
	MINIMUM	NOMINAL	MAXIMUM
N	64		
A	--	--	1.60
A1	0.05	--	0.15
A2	1.35	1.40	1.45
b	0.17	--	0.27
c	0.09	--	0.20
D	12.00 BASIC		
D1	10.00 BASIC		
D2	7.50 Ref.		
E	12.00 BASIC		
E1	10.00 BASIC		
E2	7.50 Ref.		
e	0.50 BASIC		
L	0.45	--	0.75
θ	0°	--	7°
ccc	--	--	0.08

Reference Document: JEDEC Publication 95, MS-026

TABLE 10. ORDERING INFORMATION

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
8761CYILF	ICS8761CYILF	64 lead "Lead Free" LQFP	Tray	-40°C to +85°C
8761CYILF	ICS8761CYILF	64 lead "Lead Free" LQFP	Tape and Reel	-40°C to +85°C

REVISION HISTORY SHEET				
Rev	Table	Page	Description of Change	Date
A	T10	1 9 13	Features Section - added Lead-Free bullet. Added Crystal Section. Ordering Information Table - added Lead-Free Part Number. Updated format throughout the data sheet.	10/5//04
B	T2 T5 T10	3 6 9 10 11 14	Pin Characteristics Table - changed C_{IN} from 4pF max. to 4pF typical. Crystal Characteristics Table - added Drive Level. Power Supply Filtering Techniques - corrected last sentence in the paragraph to read "Figure 1 illustrates how a ferrite bead along..." from "Figure 1 illustrates how a 10Ω resistor along...". Corrected Power Supply Filtering diagram. Added <i>Recommendations for Unused Input and Output Pins</i> . Corrected Schematic Example diagram. Ordering Information Table - added Lead-Free note.	1/13/06
B	T10	14 16	Updated datasheet's header/footer with IDT from ICS. Removed ICS prefix from Part/Order Number column. Added Contact Page.	7/27/10
C	T10	1 14	Removed ICS from part numbers where needed. Features Section - removed reference to leaded package. Ordering Information - removed quantity from tape and reel. Deleted LF note below the table. Updated header and footer.	1/25/16



Corporate Headquarters
6024 Silver Creek Valley Road
San Jose, CA 95138 USA
www.IDT.com

Sales
1-800-345-7015 or 408-284-8200
Fax: 408-284-2775
www.IDT.com/go/sales

Tech Support
www.idt.com/go/support

DISCLAIMER Integrated Device Technology, Inc. (IDT) reserves the right to modify the products and/or specifications described herein at any time, without notice, at IDT's sole discretion. Performance specifications and operating parameters of the described products are determined in an independent state and are not guaranteed to perform the same way when installed in customer products. The information contained herein is provided without representation or warranty of any kind, whether express or implied, including, but not limited to, the suitability of IDT's products for any particular purpose, an implied warranty of merchantability, or non-infringement of the intellectual property rights of others. This document is presented only as a guide and does not convey any license under intellectual property rights of IDT or any third parties.

IDT's products are not intended for use in applications involving extreme environmental conditions or in life support systems or similar devices where the failure or malfunction of an IDT product can be reasonably expected to significantly affect the health or safety of users. Anyone using an IDT product in such a manner does so at their own risk, absent an express, written agreement by IDT.

Integrated Device Technology, IDT and the IDT logo are trademarks or registered trademarks of IDT and its subsidiaries in the United States and other countries. Other trademarks used herein are the property of IDT or their respective third party owners.

For datasheet type definitions and a glossary of common terms, visit www.idt.com/go/glossary.

Copyright ©2016 Integrated Device Technology, Inc. All rights reserved.